

SN54107, SN54LS107A,
SN74107, SN74LS107A
DUAL J-K FLIP-FLOPS WITH CLEAR
SDLS036 – DECEMBER 1983 – REVISED MARCH 1988

- Package Options Include Plastic "Small Outline" Packages, Ceramic Chip Carriers, and Plastic and Ceramic DIPs
- Dependable Texas Instruments Quality and Reliability

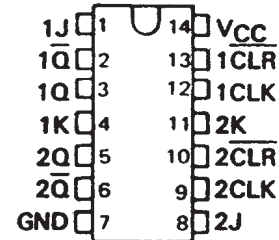
description

The '107 contain two independent J-K flip-flops with individual J-K, clock, and direct clear inputs. The '107 is a positive pulse-triggered flip-flop. The J-K input data is loaded into the master while the clock is high and transferred to the slave and the outputs on the high-to-low clock transistion. For these devices the J and K inputs must be stable while the clock is high.

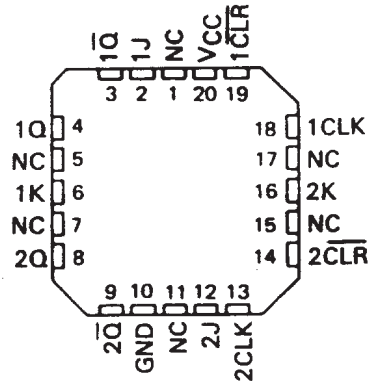
The 'LS107A contain two independent negative-edge-triggered flip-flops. The J and K inputs must be stable prior to the high-to-low clock transition for predictable operation. When the clear is low, it overrides the clock and data inputs forcing the Q output low and the $\bar{Q}$ output high.

The SN54107 and the SN54LS107A are characterized for operation over the full military temperature range of -55°C to 125°C. The SN74107 and the SN74LS107A are characterized for operation from 0°C to 70°C.

SN54107, SN54LS107A . . . J PACKAGE
SN74107 . . . N PACKAGE
SN74LS107A . . . D OR N PACKAGE
(TOP VIEW)



SN54LS107A . . . FK PACKAGE
(TOP VIEW)



NC - No internal connection

'107
FUNCTION TABLE

INPUTS				OUTPUTS	
$\overline{\text{CLR}}$	CLK	J	K	Q	$\bar{Q}$
L	X	X	X	L	H
H	$\downarrow$	L	L	Q_0	$\bar{Q}_0$
H	$\downarrow$	H	L	H	L
H	$\downarrow$	L	H	L	H
H	$\downarrow$	H	H	TOGGLE	

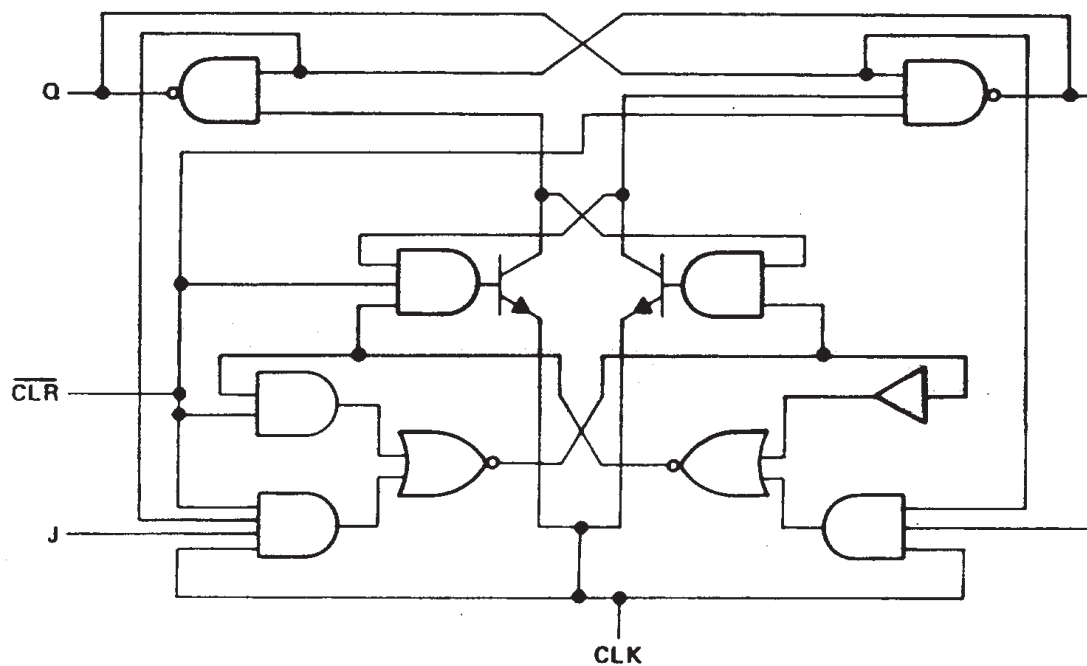
'LS107A
FUNCTION TABLE

INPUTS				OUTPUTS	
$\overline{\text{CLR}}$	CLK	J	K	Q	$\bar{Q}$
L	X	X	X	L	H
H	$\downarrow$	L	L	Q_0	$\bar{Q}_0$
H	$\downarrow$	H	L	H	L
H	$\downarrow$	L	H	L	H
H	$\downarrow$	H	H	TOGGLE	
H	H	X	X	Q_0	$\bar{Q}_0$

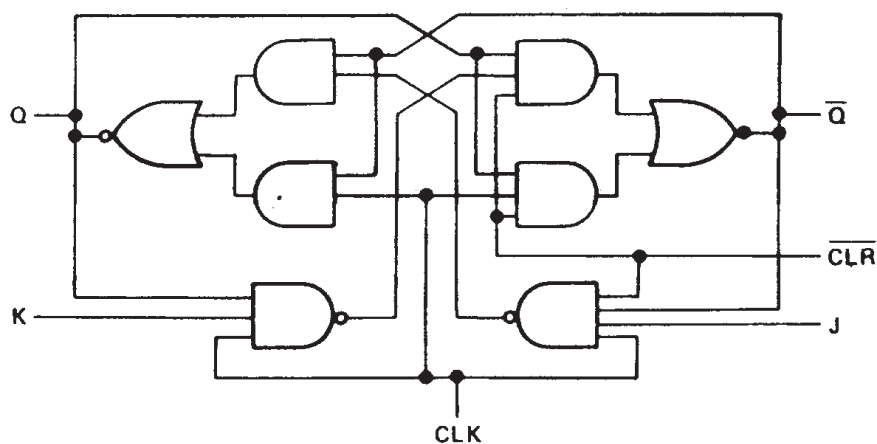
SN54107, SN54LS107A,
SN74107, SN74LS107A
DUAL J-K FLIP-FLOPS WITH CLEAR

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logic diagrams (positive logic)



'LS107A

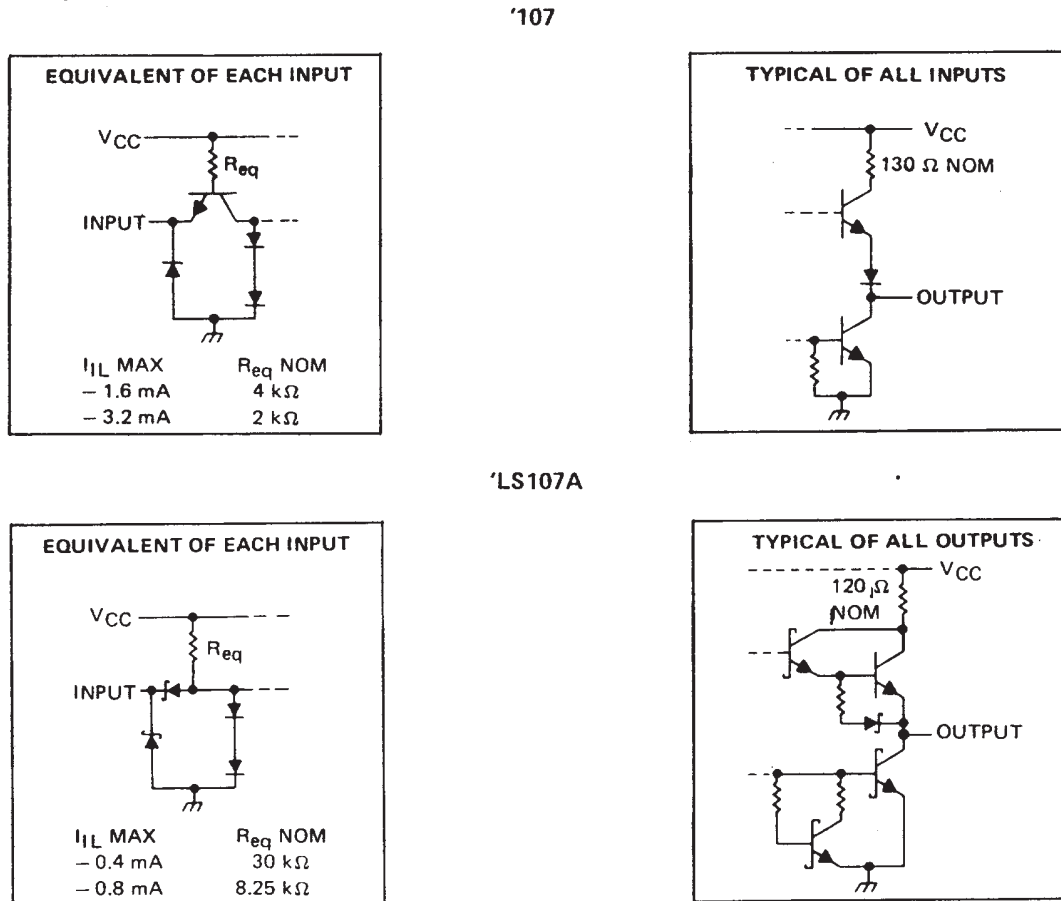


logic symbols†



†These symbols are in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.
Pin numbers shown are for D, J, and N packages.

schematic of inputs and outputs



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, V_{CC} (see Note 1)	7 V
Input voltage: '107	5.5 V
'LS107A	7 V
Operating free-air temperature range: SN54'	-55°C to 125°C
SN74'	0°C to 70°C
Storage temperature range	-65°C to 150°C

NOTE 1: Voltage values are with respect to network ground terminal.

SN54107, SN74107

DUAL J-K FLIP-FLOPS WITH CLEAR

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recommended operating conditions

		SN54107			SN74107			UNIT
		MIN	NOM	MAX	MIN	NOM	MAX	
V _{CC}	Supply voltage	4.5	5	5.5	4.75	5	5.25	V
V _{IH}	High-level input voltage	2			2			V
V _{IL}	Low-level input voltage			0.8			0.8	V
I _{OH}	High-level output current			− 0.4			− 0.4	mA
I _{OL}	Low-level output current			16			16	mA
t _w	Pulse duration	CLK high			20			ns
		CLK low			47			
		CLR low			25			
t _{su}	Input setup time before CLK†	0			0			ns
t _h	Input hold time-data after CLK†	0			0			ns
T _A	Operating free-air temperature	− 55			125			°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS†		SN54107			SN74107			UNIT
				MIN	TYP‡	MAX	MIN	TYP‡	MAX	
V_{IK}		$V_{CC} = \text{MIN}, I_I = -12 \text{ mA}$				– 1.5			– 1.5	V
V_{OH}		$V_{CC} = \text{MIN}, V_{IH} = 2 \text{ V}, V_{IL} = 0.8 \text{ V}, I_{OH} = -0.4 \text{ mA}$		2.4	3.4		2.4	3.4		V
V_{OL}		$V_{CC} = \text{MIN}, V_{IH} = 2 \text{ V}, V_{IL} = 0.8 \text{ V}, I_{OL} = 16 \text{ mA}$			0.2	0.4		0.2	0.4	V
I_I		$V_{CC} = \text{MAX}, V_I = 5.5 \text{ V}$				1			1	mA
I_{IH}	J or K	$V_{CC} = \text{MAX}, V_I = 2.4 \text{ V}$				40			40	μA
	All other					80			80	
I_{IL}	J or K	$V_{CC} = \text{MAX}, V_I = 0.4 \text{ V}$				– 1.6			– 1.6	mA
	All other					– 3.2			– 3.2	
$I_{OS}§$		$V_{CC} = \text{MAX}$		– 20		– 57	– 18		– 57	mA
$I_{CC}¶$		$V_{CC} = \text{MAX},$ See Note 2			10	20		10	20	mA

†For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

‡All typical values are at $V_{CC} = 5 \text{ V}, T_A = 25^\circ \text{C}$.

§Not more than one output should be shorted at a time.

¶Average per flip-flop.

NOTE 2: With all outputs open, I_{CC} is measured with the Q and $\bar{Q}$ outputs high in turn. At the time of measurement, the clock input is grounded.

switching characteristics, $V_{CC} = 5 \text{ V}, T_A = 25^\circ \text{C}$ (see note 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS		MIN	TYP	MAX	UNIT
f_{max}			$R_L = 400 \Omega, C_L = 15 \text{ pF}$		15	20		MHz
t_{PLH}	$\overline{\text{CLR}}$	$\bar{Q}$				16	25	ns
t_{PHL}		Q				25	40	ns
t_{PLH}	CLK	Q or $\bar{Q}$				16	25	ns
t_{PHL}						25	40	ns

NOTE 3: Load circuits and voltage waveforms are shown in Section 1.



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SN54LS107A, SN74LS107A DUAL J-K FLIP-FLOPS WITH CLEAR

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recommended operating conditions

		SN54LS107A			SN74LS107A			UNIT		
		MIN	NOM	MAX	MIN	NOM	MAX			
V _{CC}	Supply voltage	4.5	5	5.5	4.75	5	5.25	V		
V _{IH}	High-level input voltage	2			2			V		
V _{IL}	Low-level input voltage			0.7			0.8	V		
I _{OH}	High-level output current			− 0.4			− 0.4	mA		
I _{OL}	Low-level output current			4			8	mA		
f _{clock}	Clock frequency	0		30	0		30	MHz		
t _w	Pulse duration	CLK high			20			ns		
		CLR low			25					
t _{su}	Setup time before CLK ↓	data high or low			20			ns		
		CLR inactive			25					
t _h	Hold time-data after CLK ↓	0			0			ns		
T _A	Operating free-air temperature	− 55			125			0	70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS†	SN54LS107A		SN74LS107A		UNIT
			MIN	TYP‡ MAX	MIN	TYP‡ MAX	
V _{IK}		V _{CC} = MIN, I _I = – 18 mA	– 1.5		– 1.5		V
V _{OH}		V _{CC} = MIN, V _{IH} = 2 V, V _{IL} = MAX, I _{OH} = – 0.4 mA	2.5	3.4	2.7	3.4	V
V _{OL}		V _{CC} = MIN, V _{IL} = MAX, V _{IH} = 2 V, I _{OL} = 4 mA	0.25 0.4		0.25 0.4		V
		V _{CC} = MIN, V _{IL} = MAX, V _{IH} = 2 V, I _{OL} = 8 mA			0.35 0.5		
I _I	J or K	V _{CC} = MAX, V _I = 7 V	0.1		0.1		mA
	CLR		0.3		0.3		
	CLK		0.4		0.4		
I _{IH}	J or K	V _{CC} = MAX, V _I = 2.7 V	20		20		μA
	CLR		60		60		
	CLK		80		80		
I _{IL}	J or K	V _{CC} = MAX, V _I = 0.4 V	– 0.4		– 0.4		mA
	CLR or CLK		– 0.8		– 0.8		
I _{OS} §		V _{CC} = MAX, See Note 4	– 20	– 100	– 20	– 100	mA
I _{CC} (Total)		V _{CC} = MAX, See Note 2	4 6		4 6		mA

† For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

‡ All typical values are at V_{CC} = 5 V, T_A = 25°C.

§ Not more than one output should be shorted at a time, and the duration of the short circuit should not exceed one second.

NOTE 2: With all outputs open, I_{CC} is measured with the Q and $\bar{Q}$, outputs high in turn. At the time of measurement, the clock input is grounded.

NOTE 4: For certain devices where state commutation can be caused by shorting an output to ground, an equivalent test may be performed with V_O = 2.25 V and 2.125 V for the 54 family and the 74 family, respectively, with the minimum and maximum limits reduced to one half of their stated values.

switching characteristics, V_{CC} = 5 V, T_A = 25°C (see note 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	MIN	TYP	MAX	UNIT
f _{max}			R _L = 2 kΩ, C _L = 15 pF	30	45		MHz
t _{PLH}	CLR or CLK	Q or Q̄			15	20	ns
t _{PHL}					15	20	ns

NOTE 3: Load circuits and voltage waveforms are shown in Section 1.



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